

GENERAL DESCRIPTION

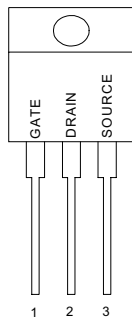
This advanced high voltage MOSFET is designed to withstand high energy in the avalanche mode and switch efficiently. This new high energy device also offers a drain-to-source diode with fast recovery time. Designed for high voltage, high speed switching applications such as power supplies, converters, power motor controls and bridge circuits.

FEATURES

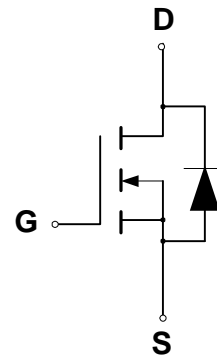
- ◆ Higher Current Rating
- ◆ Lower Rds(on)
- ◆ Lower Capacitances
- ◆ Lower Total Gate Charge
- ◆ Tighter VSD Specifications
- ◆ Avalanche Energy Specified

PIN CONFIGURATION

TO-220FP
Top View



SYMBOL



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Drain to Current – Continuous	I_D	3.0	A
– Pulsed	I_{DM}	12	
Gate-to-Source Voltage – Continue	V_{GS}	±30	V
– Non-repetitive	V_{GSM}	±40	V
Total Power Dissipation	P_D	35	W
Derate above 25°C		0.28	W/°C
Operating and Storage Temperature Range	T_J, T_{STG}	-65 to 150	°C
Single Pulse Drain-to-Source Avalanche Energy – $T_J = 25^\circ\text{C}$ ($V_{DD} = 50\text{V}, V_{GS} = 10\text{V}, I_D = 3\text{A}, L = 10\text{mH}, R_G = 25\Omega$)	E_{AS}	176	mJ
Thermal Resistance – Junction to Case	θ_{JC}	1.70	°C/W
– Junction to Ambient	θ_{JA}	62	
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 10 seconds	T_L	300	°C

ORDERING INFORMATION

Part Number	Package
STP3NB80	TO-220 Full Package

ELECTRICAL CHARACTERISTICS

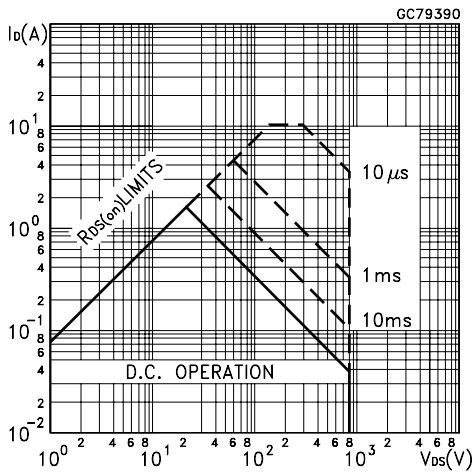
Unless otherwise specified, $T_J = 25\text{ }^\circ\text{C}$.

Characteristic	Symbol	STP3NB80			Units	
		Min	Typ	Max		
Drain-Source Breakdown Voltage ($V_{GS} = 0\text{ V}$, $I_D = 250\text{ }\mu\text{A}$)	$V_{(BR)DSS}$	800			V	
Drain-Source Leakage Current ($V_{DS} = 800\text{ V}$, $V_{GS} = 0\text{ V}$)	I_{DSS}			1	μA	
Gate-body Leakage Current ($V_{GS} = \pm 30\text{ V}$, $V_{DS} = 0\text{ V}$)	I_{GSS}			± 100	nA	
Gate-Source Leakage Current-Reverse ($V_{GS} = 20\text{ V}$, $V_{DS} = 0\text{ V}$)	I_{GSSR}			-100	nA	
Gate Threshold Voltage ($V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$)	$V_{GS(th)}$	3.0		5.0	V	
Static Drain-Source On-Resistance ($V_{GS} = 10\text{ V}$, $I_D = 1.5\text{ A}$) *	$R_{DS(on)}$		2.5	4.0	mhos	
Forward Transconductance ($V_{DS} = I_{D(on)} \times R_{DS(on)max}$, $I_D = 1.5\text{ A}$) *	g_{FS}	1.5			S	
Input Capacitance	$(V_{DS} = 25\text{ V}$, $V_{GS} = 0\text{ V}$, $f = 1.0\text{ MHz}$)		C_{iss}	445	580	pF
Output Capacitance			C_{oss}	60	80	pF
Reverse Transfer Capacitance			C_{rss}	7	9	pF
Turn-On Delay Time	$(V_{DD} = 400\text{ V}$, $I_D = 1.5\text{ A}$, $V_{GS} = 10\text{ V}$, $R_G = 4.7\Omega$) *		$t_{d(on)}$	12	17	ns
Rise Time			t_r	10	14	ns
Turn-Off Delay Time			$t_{d(off)}$	19	40	ns
Fall Time			t_f	10	20	ns
Total Gate Charge	$(V_{DS} = 640\text{ V}$, $I_D = 3.0\text{ A}$, $V_{GS} = 10\text{ V}$) *		Q_g	17	24	nC
Gate-Source Charge			Q_{gs}	6.5		nC
Gate-Drain Charge			Q_{gd}	7.5		nC
Internal Drain Inductance (Measured from the drain lead 0.25" from package to center of die)	L_D		4.5		nH	
Internal Drain Inductance (Measured from the source lead 0.25" from package to source bond pad)	L_S		7.5		nH	
SOURCE-DRAIN DIODE CHARACTERISTICS						
Forward On-Voltage(1)	$(I_{SD} = 3.0\text{ A}$, $di_s/dt = 100\text{ A}/\mu\text{s})$		V_{SD}		1.6	V
Forward Turn-On Time			t_{on}	**		ns
Reverse Recovery Time			t_{rr}	650		ns

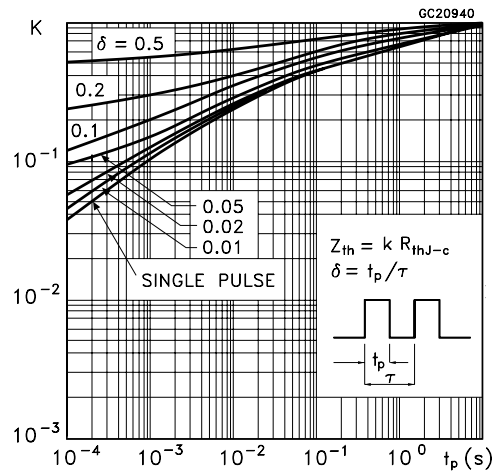
* Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$

** Negligible, Dominated by circuit inductance

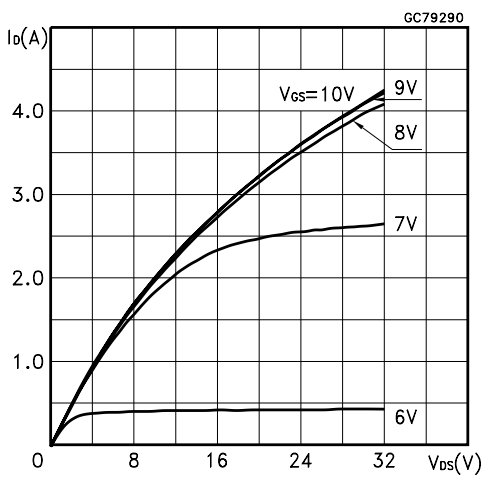
Safe Operating Area for TO-220FP



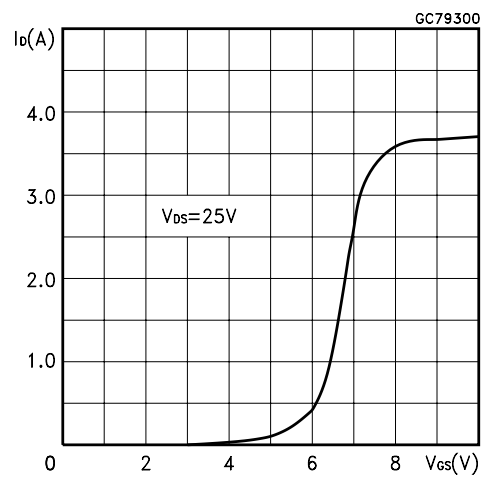
Thermal Impedance for TO-220FP



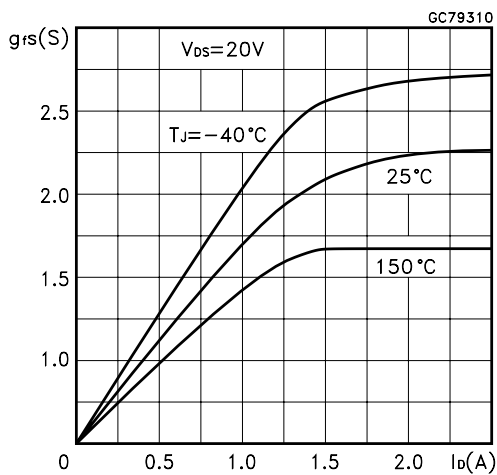
Output Characteristics



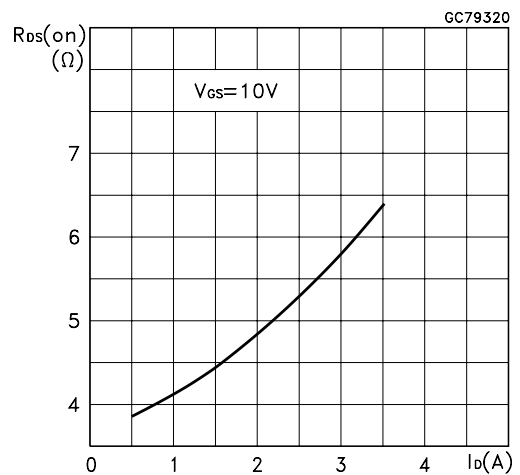
Transfer Characteristics



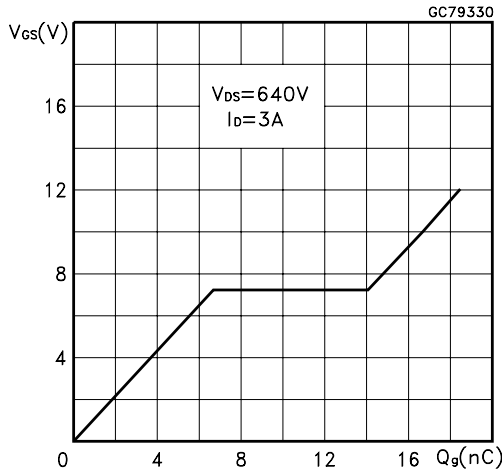
Transconductance



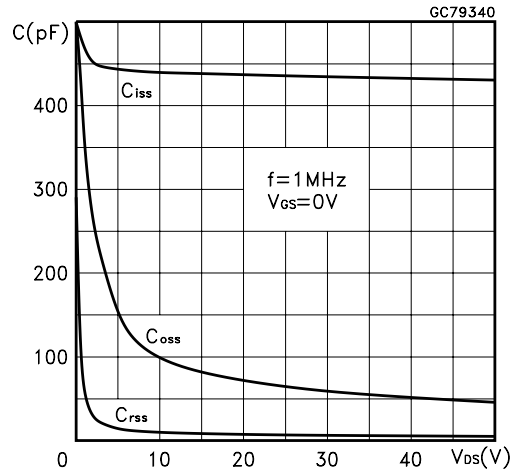
Static Drain-source On Resistance



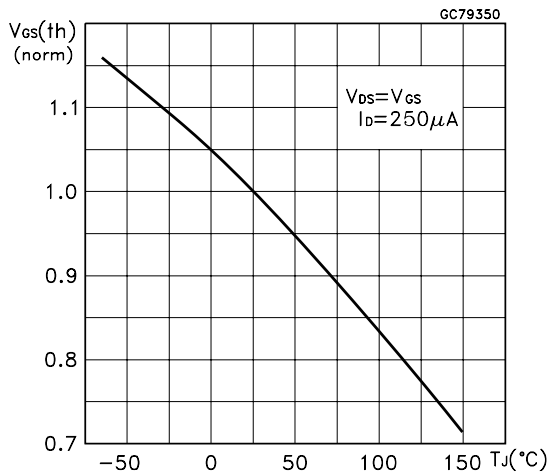
Gate Charge vs Gate-source Voltage



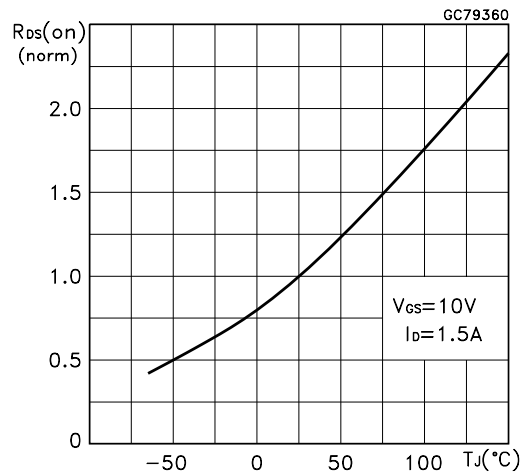
Capacitance Variations



Normalized Gate Threshold Voltage vs Temperature



Normalized On Resistance vs Temperature



Source-drain Diode Forward Characteristics

